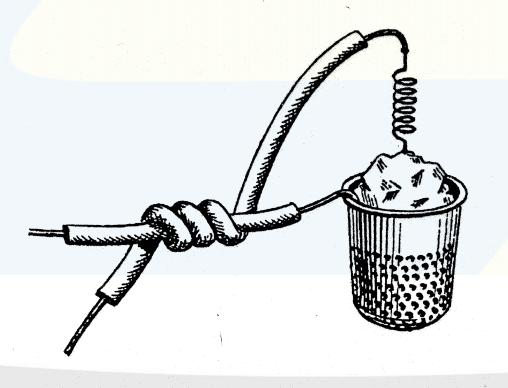


# **Sensor devices**





## Outline

- 7 Thermal sensors
  - Introduction
  - •Heat transfer
  - •Thermal structures
  - •Thermal-sensing elements
  - •Thermal and Temperature sensors



## Introduction

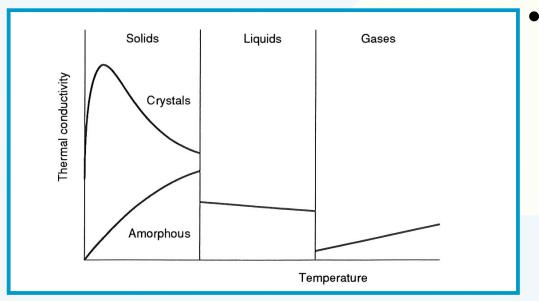
- Physical quantitaties is converted into heat
- The heat is converted into electrical quantities
- The process is done into three steps
  - Electromagnetic radiation is transduced into a heat flow
  - The heat flow is converted into a temperature difference
  - The temperature difference is transduced into a electric signal using a temperature (difference) sensor



- Heat
  - Gas and Liquid "average velocity of the molecules"
  - Solids "Phonons, vibrations of atoms in lattice and transportations of heat by free electrons"
- Specific heat and thermal capacitance
  - Heat required to increase the temperature with 1 K at constant pressure

$$c_p = \left(\frac{dH}{dT}\right)_p$$





#### Conduction

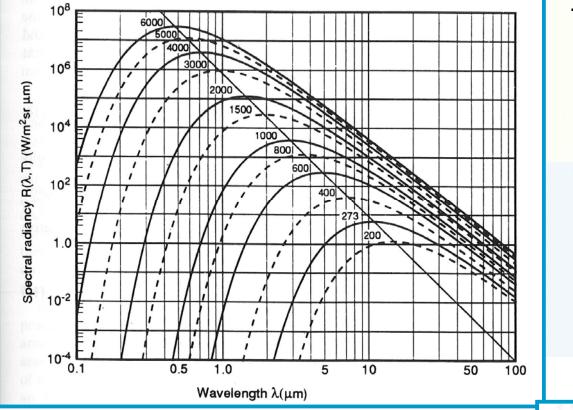
#### -Conductivity

•Heat will flow from hotter to colder region

#### -Convection

- •Heat transfer to flowing fluids (Liquid or gas)
- •Laminar flow
- Turbulent flow





#### Radiation

#### -Black-body Radiation

- •A body which absorb all of the radiation " absorptivity=1" is called a black body
- •A black-body with absorptivity=1 also have an emissivity=1
- Stefan-Boltzmann law

$$P''_{\rm rad}(T) = \epsilon \sigma T^4$$

 $\sigma = 56.7 \times 10^{-9} \text{ W/m}^2 \text{-} \text{K}^4$ .



G

 $T = T + \Delta T$ 

•Heat transfer by infrared radiation

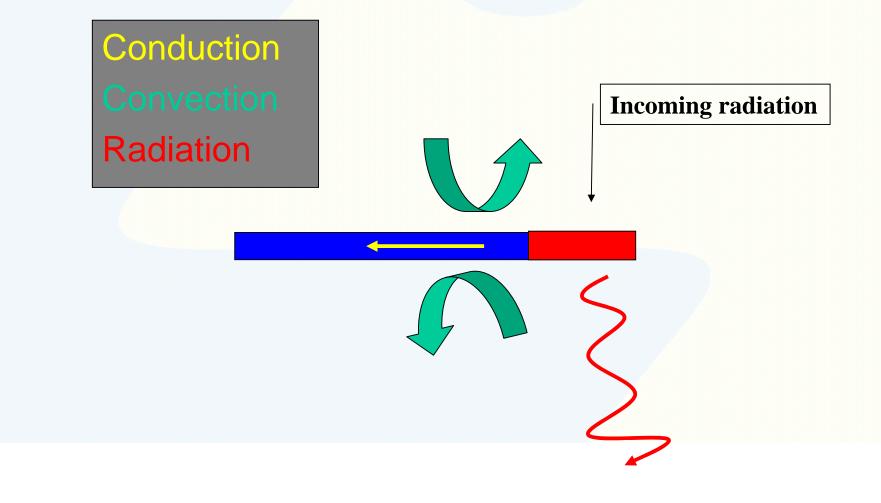
-Two parallel plates

$$G''_{\rm rad} = 4 \epsilon \sigma T^3 = \epsilon \times 6 \ {\rm W/K} \cdot {\rm m}^2.$$

•Silicon is almost transparent above 1.1 um. At room temperature the radiation have its maximum at 10 um wavelength and the absorptivity, emissivity is as low as 0.1-0.3



### **Heat transfer Summary**



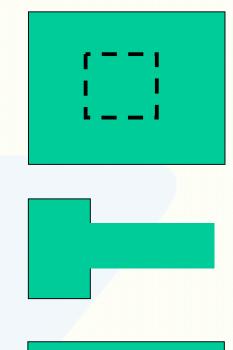


•Purpose

-Reduce "self heating" -Reduce "heat leakage" In case of temperature difference like sensor structure, make  $R_{th}$  large  $R_{th}=\Delta T/P$ 

Often solved by using thin membranes

#### •The membrane can be of type



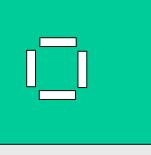




TABLE 1 Electrical Equivalents of Thermal Parameters			
Thermal Parameter	Electrical Parameter		
Temperature: T (K)	Voltage: V (V)		
Heat flow, Power: $P(W)$	Current: I (A)		
Heat: $Q (J = W s)$	Charge: $Q$ (C = A-s)		
Resistance: $R$ (K/W)	Resistance: $R (\Omega = V/A)$		
Conductance: $G(W/K)$	Conductance: $G(S = \Omega^{-1})$		
Capacity: $C$ (J/K)	Capacitance: $C$ (F = A-s/V)		
Thermal resistivity: $\rho_{th}$ (K-m/W)	Electrical resistivity: $\rho_{el}$ ( $\Omega$ -m)		
Thermal conductivity: $\kappa$ (W/K-m)	Electrical conductivity: $\sigma$ (S/m)		
Specific heat: $c_p$ (J/kg-K)	Permittivity: $\varepsilon$ (F/m)		



One dimensional heat flow

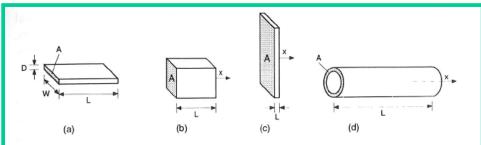


Fig. 5 One-dimensional heat flow along the axis of rods, wires, rectangular plates and tubes. The symbol L denotes the linear dimension in the direction of the heat flow. (After Ref. 1)

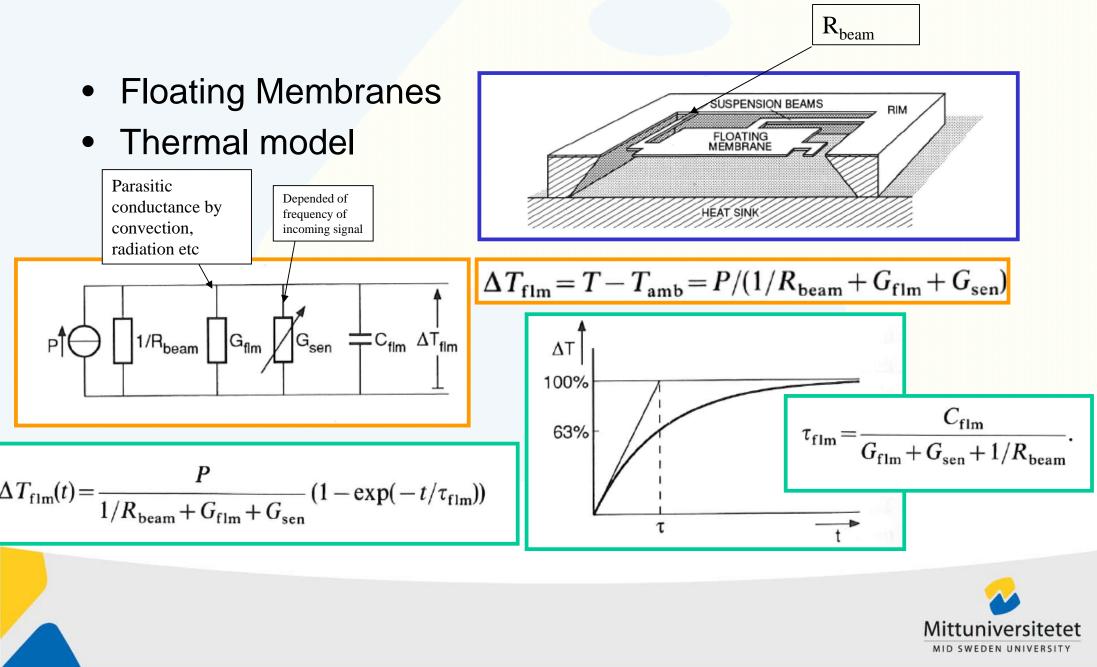
Thermal resistance 1 dimension K= thermal conductivity

$$R_{\rm th} = \frac{L}{\kappa A}$$

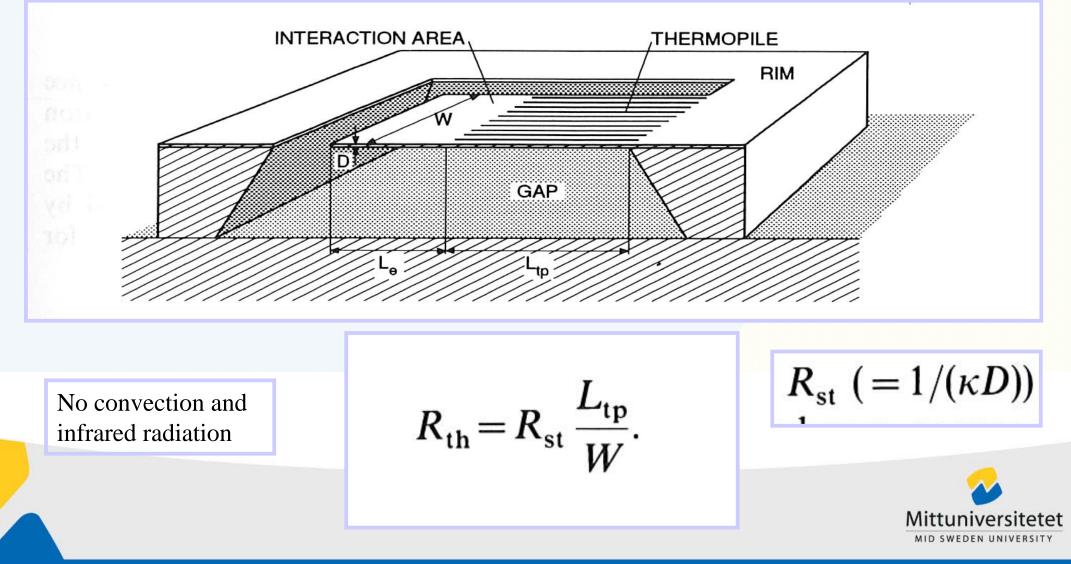
Thermal resistance of object in fig 5a

$$R_{\rm th} = \frac{L}{W} \frac{1}{\kappa D}.$$



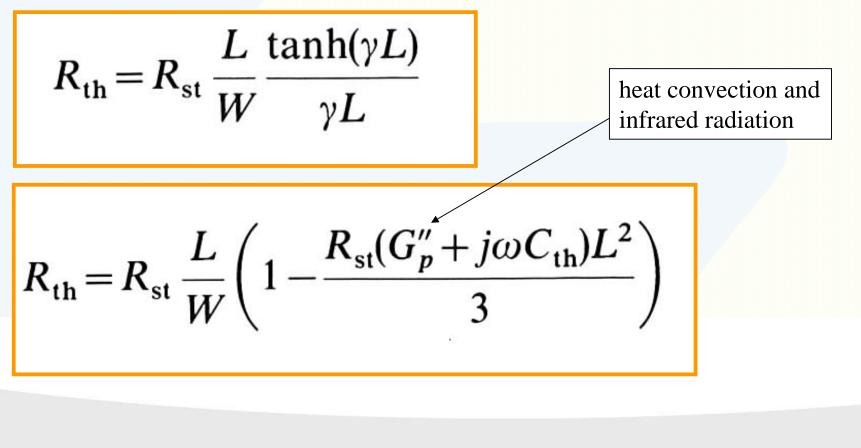


#### Cantilever beam and bridges



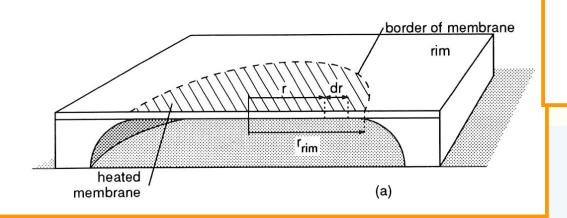
Cantilever beam and bridges

In case of heat convection and infrared radiation





#### **Closed membranes**



$$T(r) = P'' R_{\rm st} (r_{\rm rim}^2 - r^2)/4$$

$$P''$$
 (in W/m<sup>2</sup>)

Uniform heating of membrane with power density *P*<sup>~~</sup>

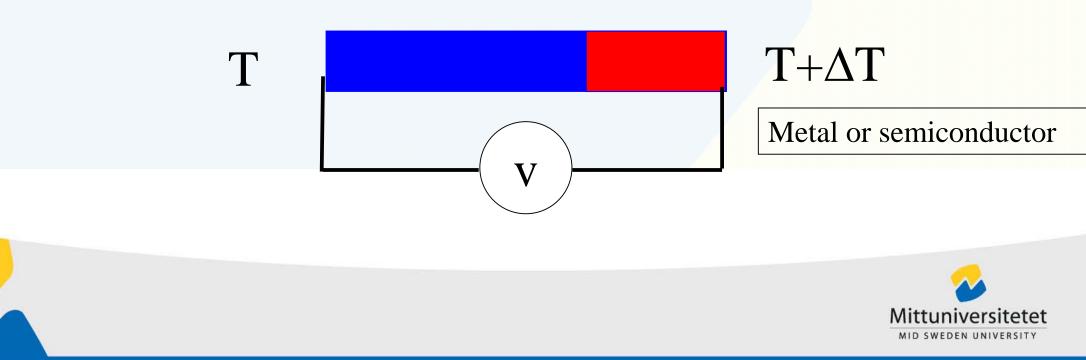


- Resistors
  - Bridge coupled mono or poly silicon resistors
  - Platinum resistors Pt100, 100ohm at 0°C, 0.38%/K
- Thermopile
- Acoustic sensing elements



$$\Delta V = \alpha_S \Delta T$$

 $\alpha_s$  is the Seebeck coefficient expressed in V/K.

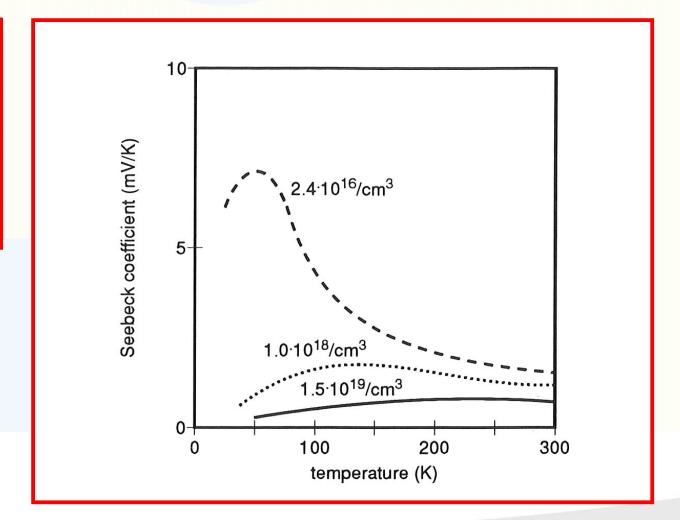


#### Seebeck Coefficients

Material	273 K		300 K
<i>p</i> -type mono silicon (Si)			300 to 1000
Antimony (Sb)		43ª	
Chrome (Cr)	18.8		17.3
Gold (Au)	1.79		1.94
Copper (Cu)	1.70		1.83
Aluminum (Al)			-1.7
Platinum (Pt)	-4.45		-5.28
Nickel (Ni)	-18.0		
Bismuth (Bi)		$-79^{a}$	
<i>n</i> -type polysilicon (Si)			-200 to $-500$

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Seebeck Coefficients, dependencies of temperature and doping in p-type silicon





Thermopile

$$\Delta V = (S_a - S_b) \Delta T$$

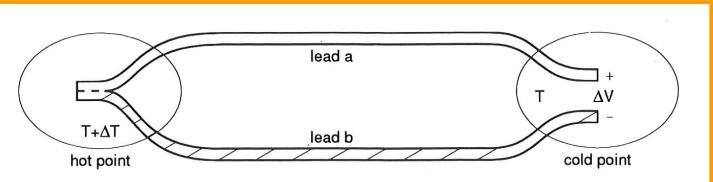


Fig. 11 The Seebeck effect: an electrical voltage  $\Delta V$  is generated due to a temperature difference  $\Delta T$ . (After Ref. 1)

Design rule number of thermopile

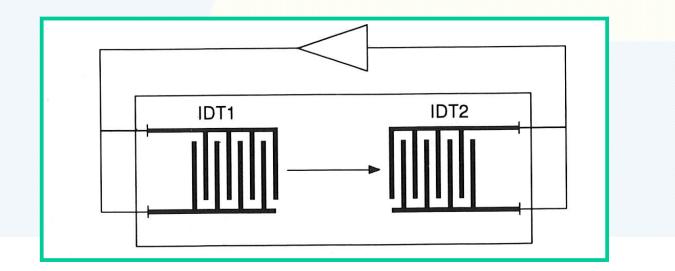
 $R_{\rm st}$ =thermal sheet resistance

 $R_{se}$  = electrical sheet resistance

$$N \simeq \sqrt{\frac{R_{\rm st}W}{R_{\rm se}L_x}}$$

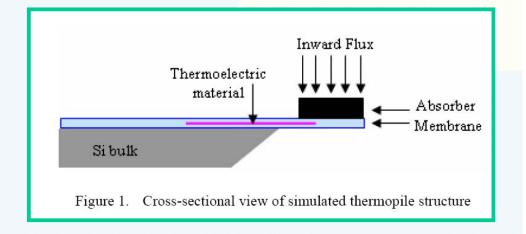


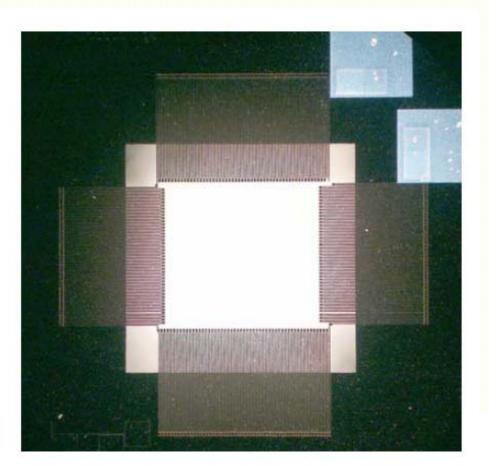
- Acoustic wave sensors
- feedback loop, oscillators
- sensitivity ~2.8kHz/°C



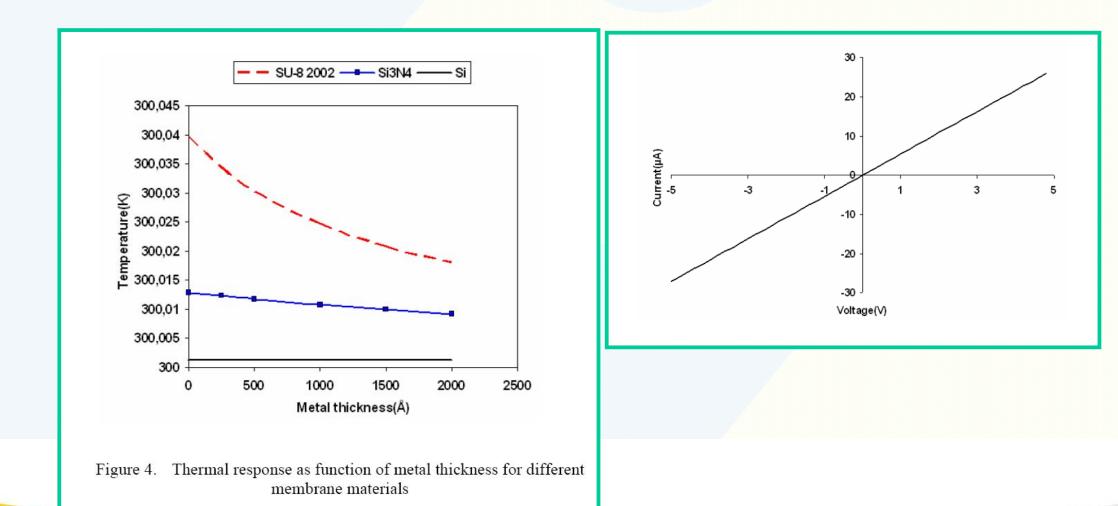


#### Thermopile, SU8 with Ni and Ti as thermopile element

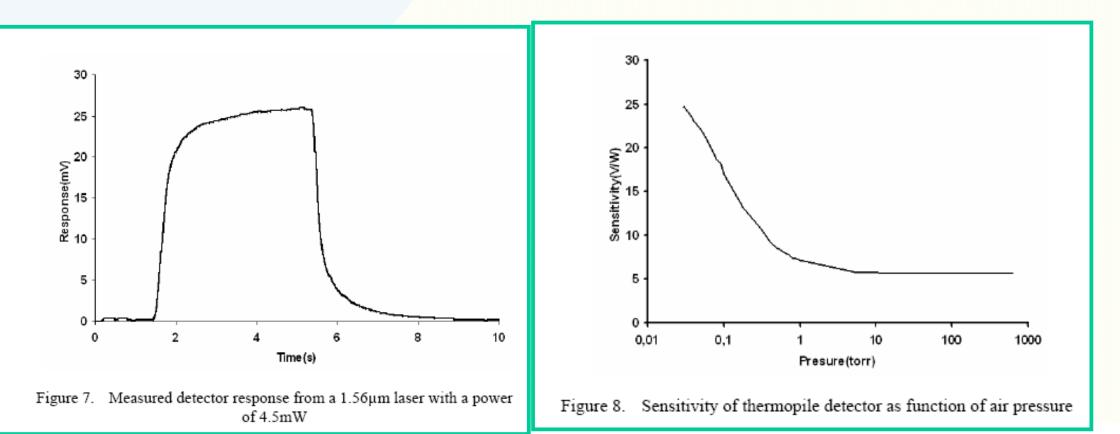




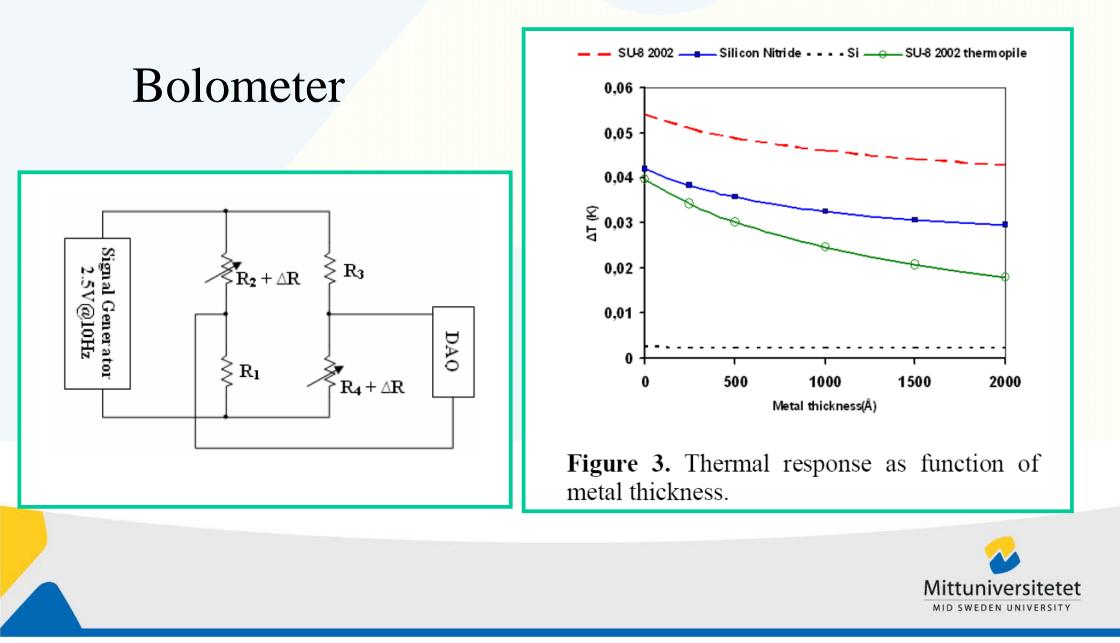




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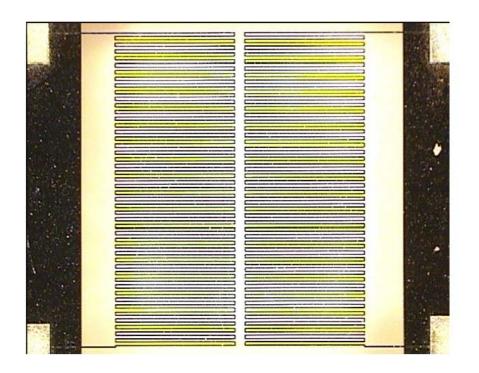
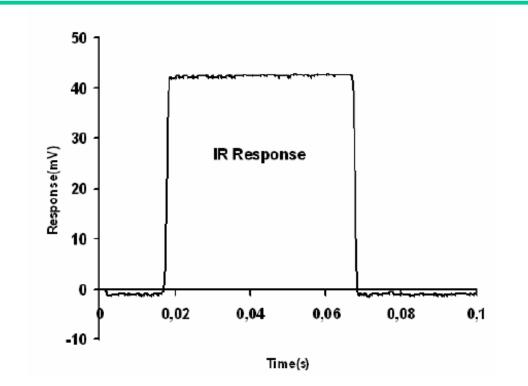
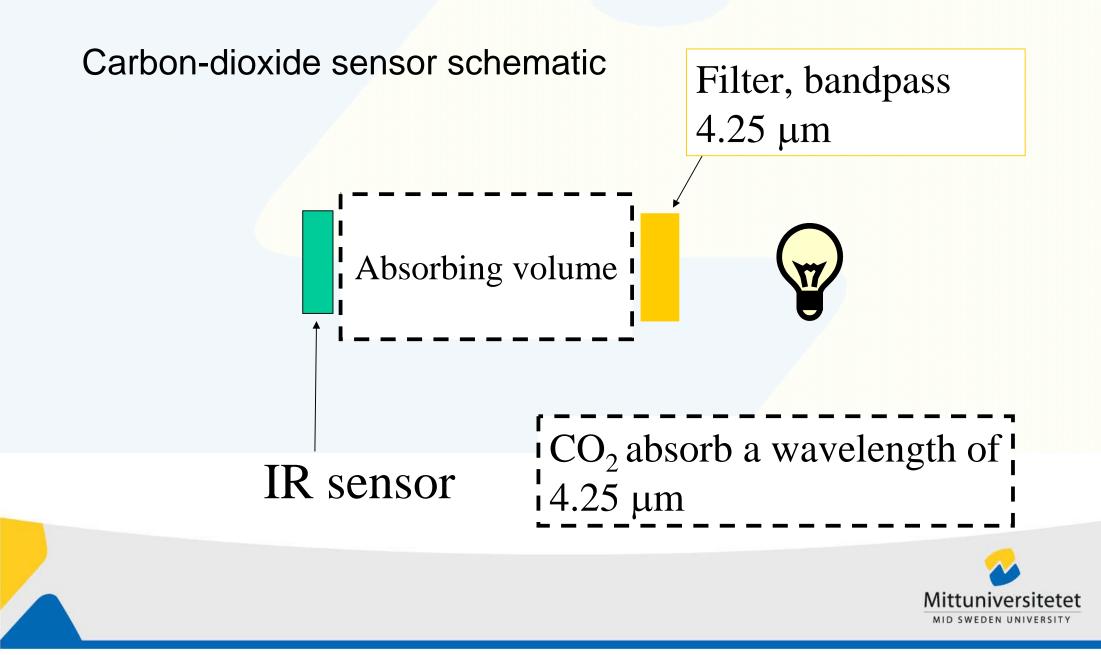


Figure 5. Top view image of IR sensitive resistances  $(R_2 \text{ and } R_4)$  on fabricated bolometer.



**Figure 6.** Measured detector response from a 1.56 µm laser with a power of 4.5 mW.





### **Exercises**

#### Processing part (chapter 2)

- **3.1** How long does it take to grow 100 nm of oxide in wet oxygen at 1000 °C (assume 100 silicon)? In dry oxygen? Which process would be preferred?
- 3.2 A 1.2-μm silicon dioxide film is grown on a <100> silicon wafer in wet oxygen at 1100 °C. How long does it take to grow the first 0.4 μm? The second 0.4μm? The final 0.4 μm?
- **4.1** A phosphorus diffusion has a surface concentration of  $5 \times 10^{18}$ /cm<sup>3</sup>, and the background concentration of the *p*-type wafer is  $1 \times 10^{15}$ /cm<sup>3</sup>. The *Dt* product for the diffusion is  $10^{-8}$  cm<sup>2</sup>.
  - (a) Find the junction depth for a Gaussian distribution.
  - (b) Find the junction depth for an erfc profile.
  - (c) What is the sheet resistance of the two diffusions?
  - (d) Draw a graph of the two profiles.

3.1 9 min, 2.3h 4:1 5.8 um, 5.3 um, 470hm/Square, 60 ohm/square



#### Exercise

- 6. Thermal Model of Floating-Membrane Sensor. A floating-membrane sensor has a suspension beam 2 mm in length, 200  $\mu$ m in width and 5  $\mu$ m in thickness ( $\kappa_{si} = 150 \text{ W/K-m}$ ). At its end a floating membrane is suspended with an area of 2 mm<sup>2</sup>, between heat sinks at 0.5 mm distance under and above the membrane. The sensor is encapsulated in argon ( $\kappa_{Ar} = 18 \text{ mW/K-m}$ ).
  - a) What is the beam's thermal resistance compared to that of the floating membrane?
  - b) How do the thermal time constants of the beam and the overall system (using a simple model) compare? Note, that the specific heat of silicon is  $c_p = 1.6 \text{ MJ/m}^3\text{-K}$ .

